



## Features

- Wide bandgap SiC MOSFET technology
- Low On-Resistance with High Blocking Voltage
- Low Capacitances with High-Speed switching
- Low reverse recovery(Qrr)
- Halogen free, RoHs compliant

## Benefits

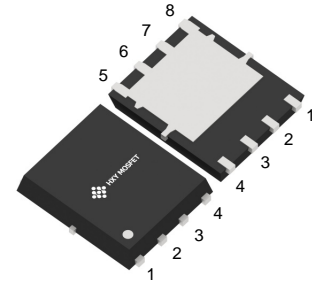
- Reduce switching losses
- Increased system Switching Frequency
- Increased power density
- Reduction of heat sink requirements

## Applications

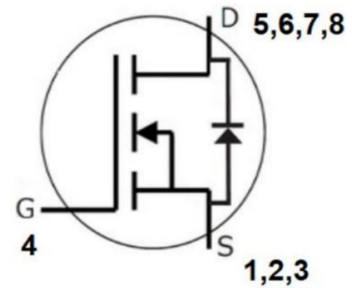
- Switch mode power supplies
- Renewable energy
- On Board Charger
- High Voltage DC/DC Converters



Ordering Part Number	Package	Brand
STL12N65M5	DFN5X6-8L	HXY MOSFET



DFN5X6-8L



## Maximum Ratings ( $T_c = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test conditions	Value	Unit	Note
$V_{DSmax}$	Drain-Source Voltage	$V_{GS} = 0V, I_D = 100\mu A$	650	V	
$V_{GS}$	Gate-Source voltage (transient)	$t_p \leq 500ns, \text{duty cycle} \leq 1\%$	-8/+20	V	
$V_{GSop}$	Recommend Gate-Source Voltage	Static	-4/+18	V	
$EAS$	Single pulse avalanche energy	$V_{DS}=650V, V_{DD}=50V, V_{GS}=10V, L=10mH, T_c=25^\circ C$	68	mJ	
$I_D$	Continuous Drain current	$V_{GS} = 18V, T_c = 25^\circ C$	9	A	Fig. 14
		$V_{GS} = 18V, T_c = 100^\circ C$	5		
$I_{D,pulse}$	Pulsed Drain Current	Pulse with $t_p$ limited by $T_{jmax}$	15	A	
$P_D$	Power Dissipation	$T_c = 25^\circ C, T_j = 175^\circ C$	43.4	W	Fig. 16
$T_j$	Operating junction temperature		-55~175	$^\circ C$	
$T_{stg}$	Storage temperature		-55~175	$^\circ C$	



### Thermal Characteristics

Symbol	Parameter	Value			Unit	Note
		Min.	Typ.	Max.		
$R_{th(jc)}$	Thermal resistance from Junction to Case		3.46		K/W	Fig. 15
$R_{th(ja)}$	Thermal resistance from Junction to Ambient		40		K/W	

### Electrical Characteristics (T<sub>c</sub> = 25°C unless other wise specified)

#### Static Characteristics

Symbol	Parameter	Test conditions	Value			Unit	Note
			Min.	Typ.	Max.		
$V_{(BR)DSS}$	Drain-Source Breakdown voltage	$V_{GS} = 0V, I_D = 100\mu A$	650			V	
$V_{GS(th)}$	Gate Threshold voltage	$V_{GS} = V_{DS}, I_D = 1mA$		2.8		V	Fig. 9
		$V_{GS} = V_{DS}, I_D = 1mA, T_j = 175^\circ C$		2.0			
$I_{GSS}$	Gate-Source Leakage current	$V_{GS} = 18V, V_{DS} = 0V$			250	nA	
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 650V, V_{GS} = 0V, T_j = 25^\circ C$		1	50	$\mu A$	
$R_{DS(on)}$	Drain-Source On-state Resistance	$V_{GS} = 15V, I_D = 3A$ $V_{GS} = 18V, I_D = 3A$		530 410	690	m $\Omega$	Fig. 3, 4, 5
		$V_{GS} = 15V, I_D = 3A, T_j = 175^\circ C$ $V_{GS} = 18V, I_D = 3A, T_j = 175^\circ C$		550 500			
$g_{fs}$	Transconductance	$V_{DS} = 18V, I_D = 3A$		2.4		S	Fig. 6
		$V_{DS} = 18V, I_D = 3A, T_j = 175^\circ C$		1.9			



### Gate Charge Characteristics

Symbol	Parameter	Test conditions	Value			Unit	Note
			Min.	Typ.	Max.		
$Q_{GS}$	Gate to Source Charge	$V_{DS} = 400V$ $I_D = 3A$ $V_{GS} = -4V/18V$		2.4		nC	Fig. 10
$Q_{GD}$	Gate to Drain Charge			4.0			
$Q_G$	Total Gate Charge			9.7			

### AC Characteristics

Symbol	Parameter	Test conditions	Value			Unit	Note
			Min.	Typ.	Max.		
$C_{iss}$	Input Capacitance	$V_{GS} = 0V, V_{DS} = 600V$ $f = 1\text{ MHz}$ $V_{AC} = 25mV$		147		pF	Fig. 13
$C_{oss}$	Output Capacitance			19		pF	
$C_{rss}$	Reverse Transfer Capacitance			2.5		pF	
$R_{G(int)}$	Internal Gate Resistance	$f = 1\text{ MHz}, V_{AC} = 25mV$		5		$\Omega$	

### Reverse Diode Characteristics

Symbol	Parameter	Test conditions	Value			Unit	Note
			Min.	Typ.	Max.		
$V_{SD}$	Diode Forward Voltage	$V_{GS} = -4V, I_{SD} = 1.5A$		4.4		V	Fig. 7,8
		$V_{GS} = -4V, I_{SD} = 1.5A, T_J = 175^\circ C$		3.9			
$I_S$	Continuous Diode Forward Current	$V_{GS} = -4V, T_C = 25^\circ C$		7		A	
$I_{S, pulse}$	Diode pulse Current	$V_{GS} = -4V$ , pulse width $t_p$ limited by $T_{jmax}$		15		A	



## Typical Performance

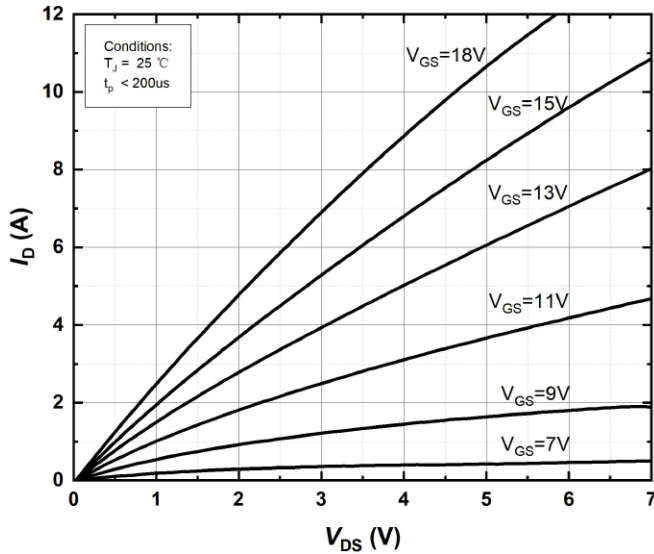


Figure 1. Output characteristics at  $T_j=25^\circ\text{C}$

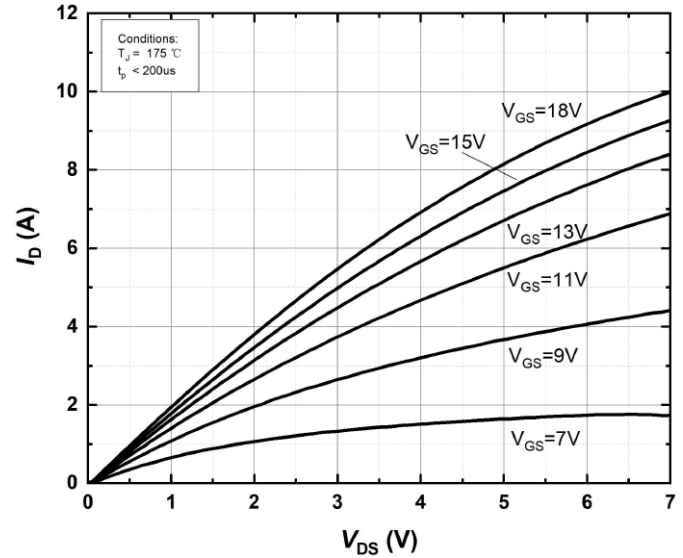


Figure 2. Output characteristics at  $T_j=175^\circ\text{C}$

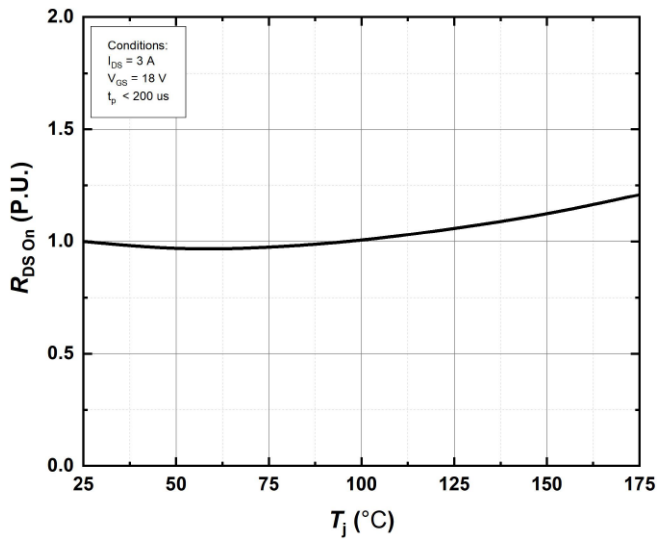


Figure 3. Normalized On-Resistance vs. Temperature

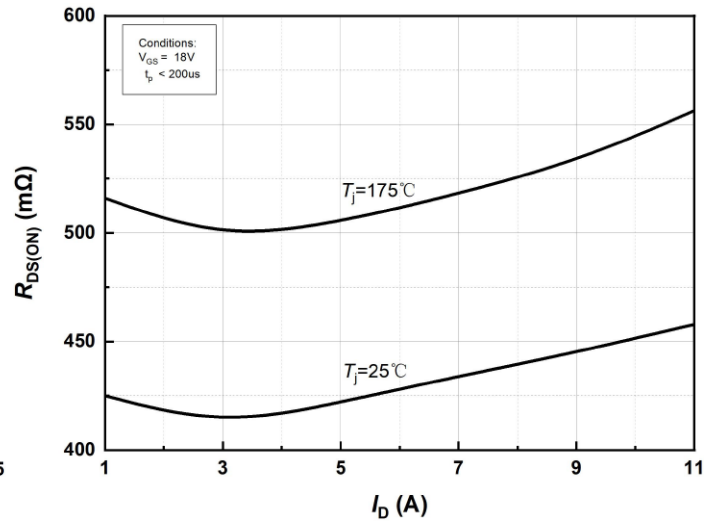


Figure 4. On-Resistance vs. Drain current for Various Temperature

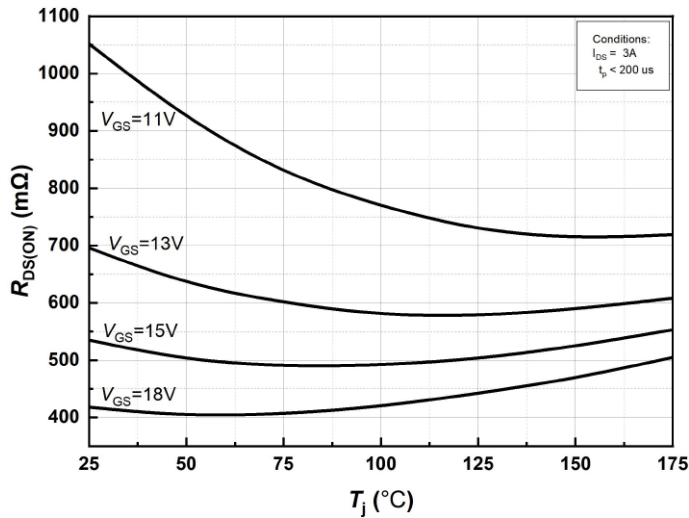


Figure 5. On-Resistance vs. Temperature for Various Gate Voltage

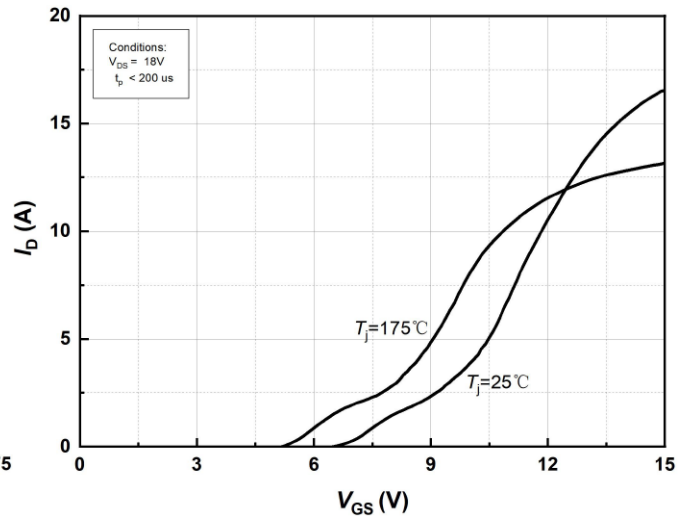


Figure 6. Transfer Characteristics for Various Junction Temperatures

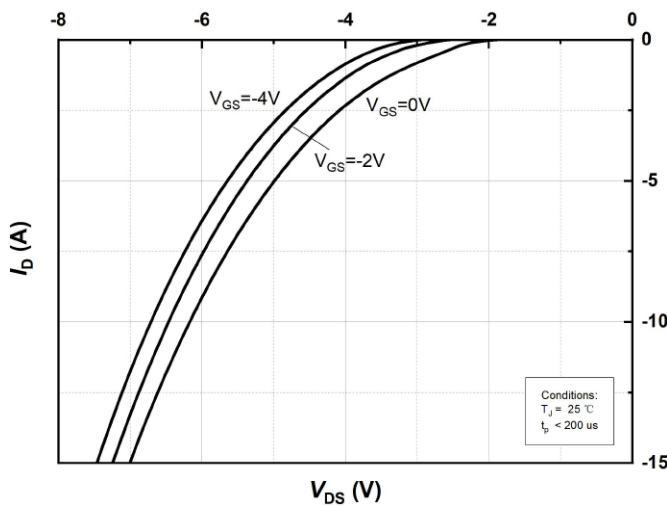


Figure 7. Body Diode Characteristics at  $T_J=25^\circ C$

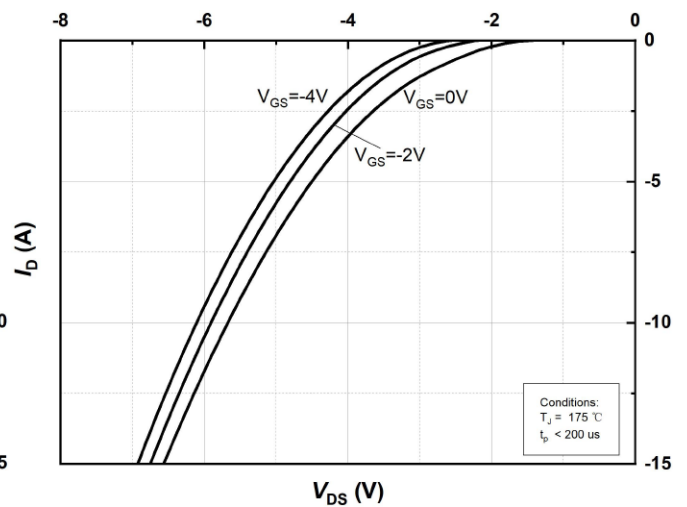


Figure 8. Body Diode Characteristics at  $T_J=175^\circ C$

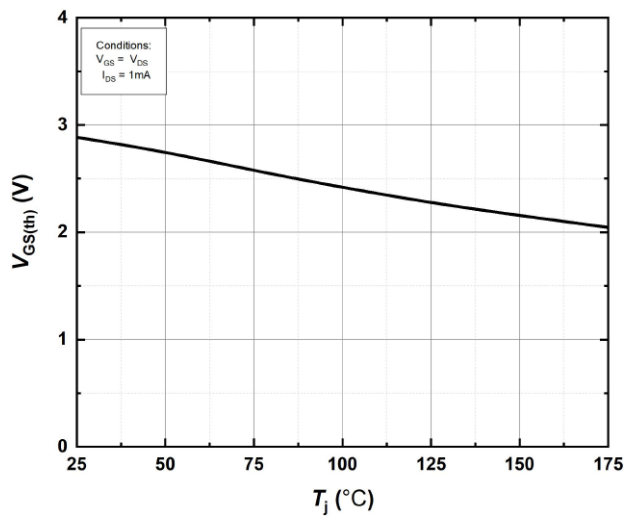


Figure 9. Threshold Voltage vs. Temperature

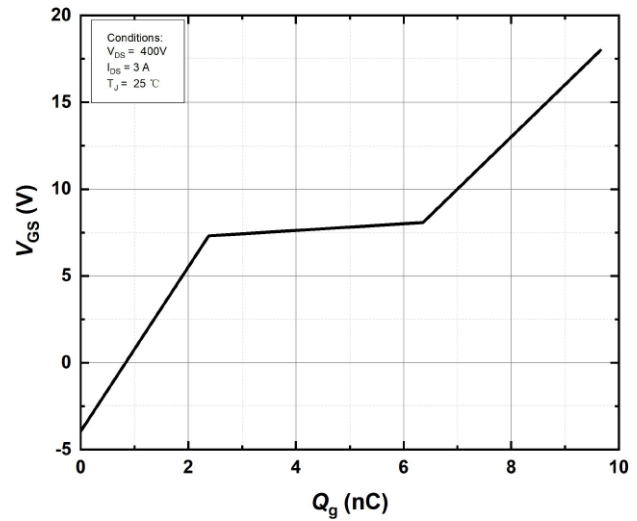


Figure 10 Gate Charge Characteristics

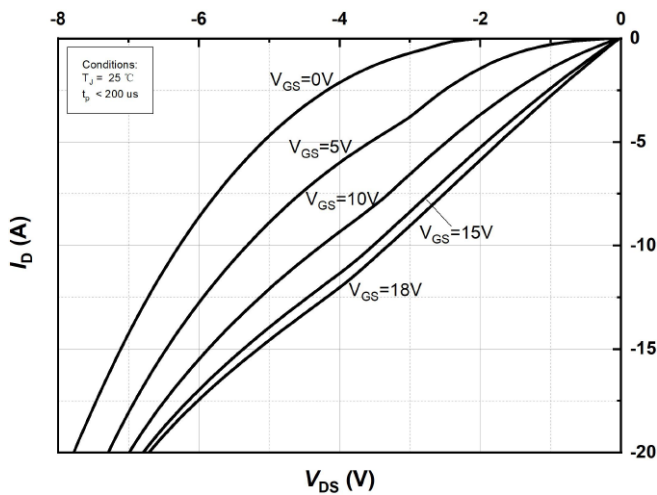


Figure 11. 3rd Quadrant Characteristic at  $T_j=25^\circ C$

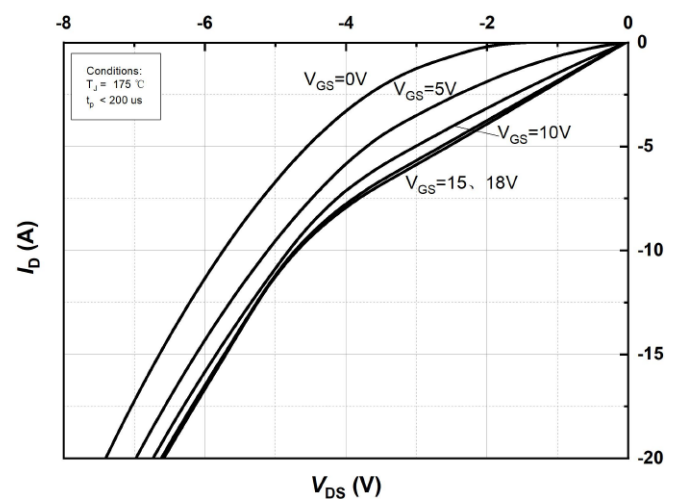


Figure 12. 3rd Quadrant Characteristic at  $T_j=175^\circ C$

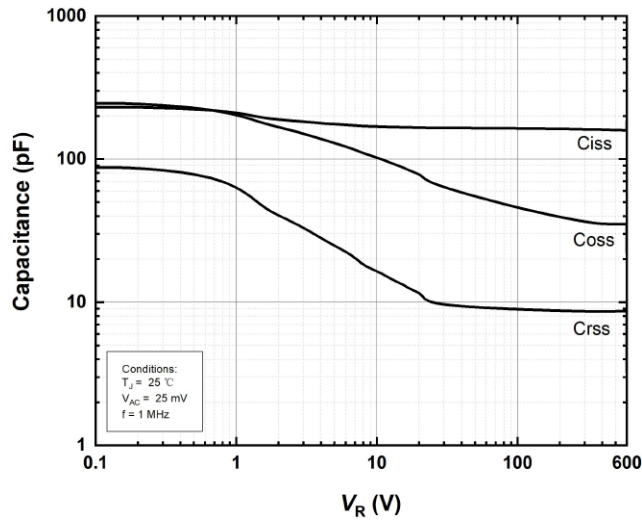


Figure 13. Capacitances vs. Drain-Source Voltage (0 – 600V)

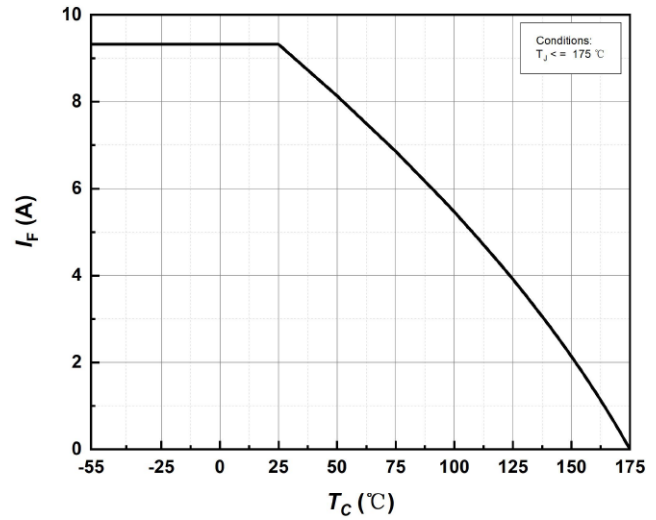


Figure 14. Continuous Drain Current Derating vs Case Temperature

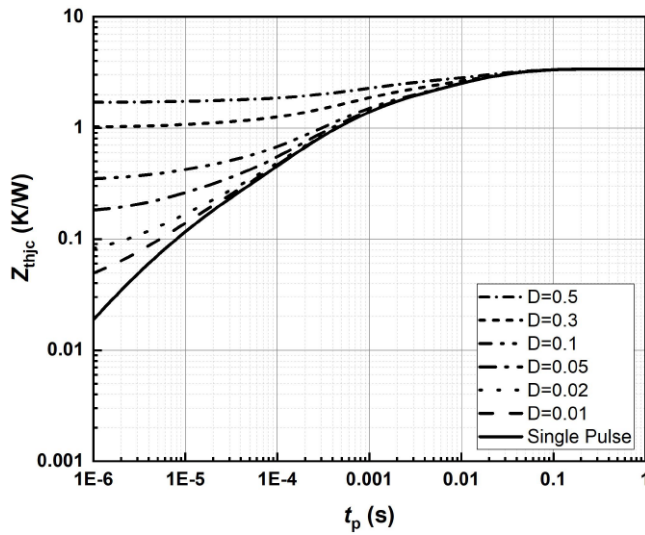


Figure 15. Transient Thermal Impedance (Junction – Case)

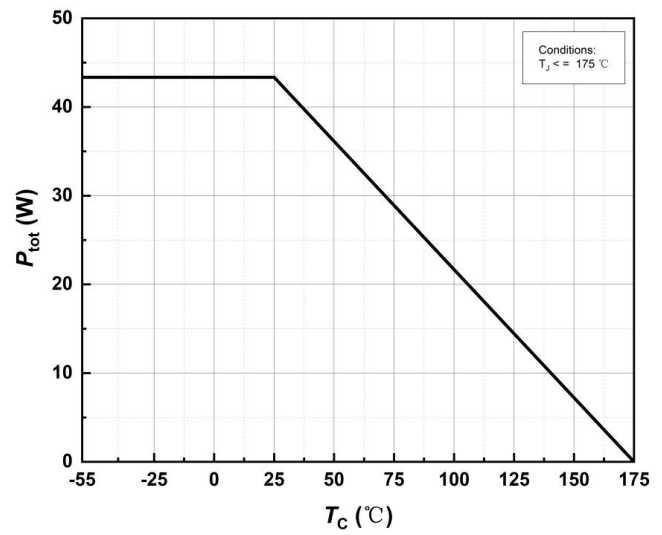


Figure 16. Maximum Power Dissipation Derating vs. Case Temperature

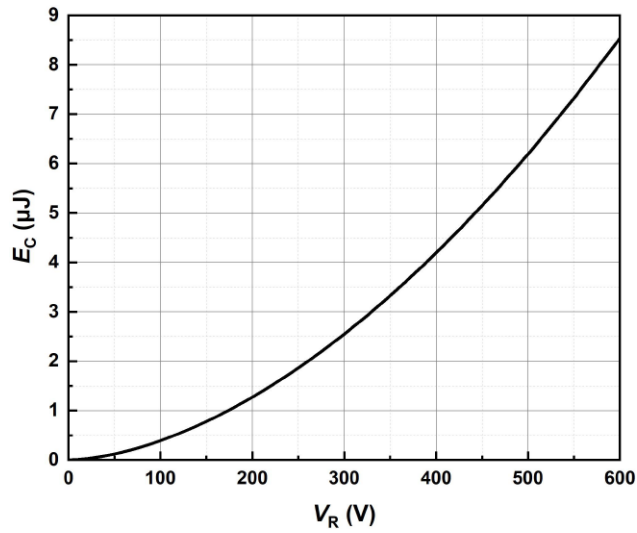


Figure 17. Output Capacitor Stored Energy

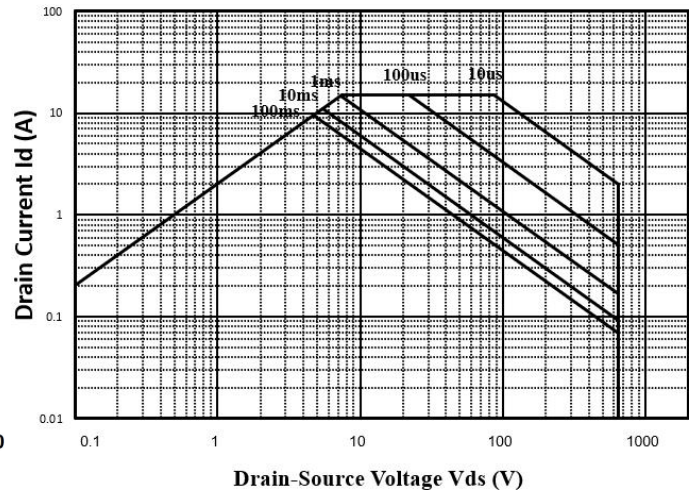
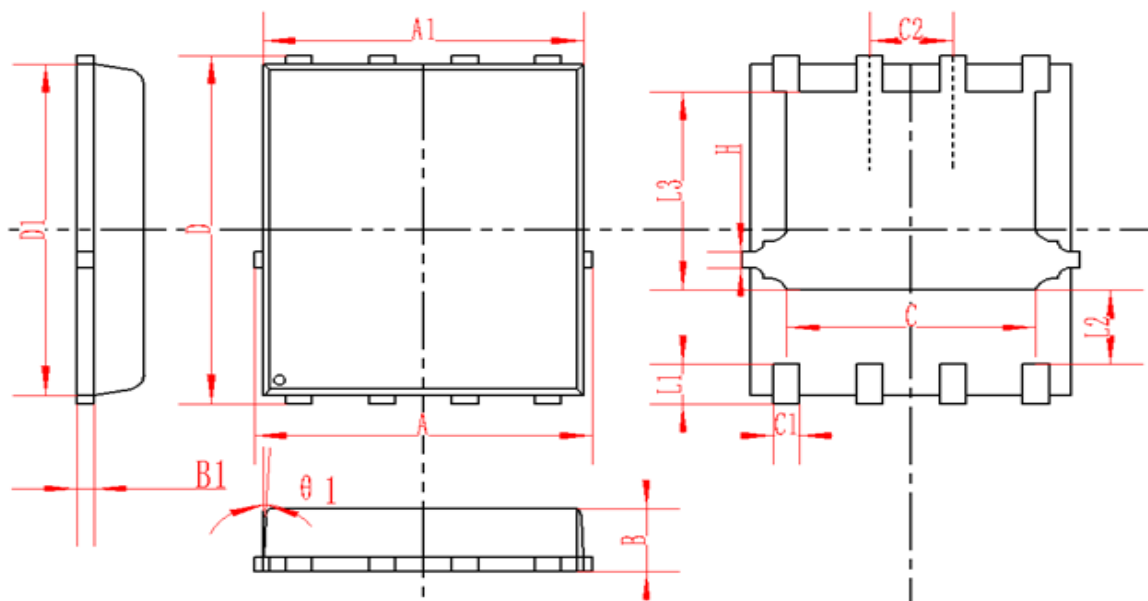


Figure 18. Safe Operating Area



## Package Dimensions

Package DFN5X6-8L



SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX
A	4.95	5	5.05	0.195	0.197	0.199
A1	4.82	4.9	4.98	0.190	0.193	0.196
D	5.98	6	6.02	0.235	0.236	0.237
D1	5.67	5.75	5.83	0.223	0.226	0.230
B	0.9	0.95	1	0.035	0.037	0.039
B1	0.254REF			0.010REF		
C	3.95	4	4.05	0.156	0.157	0.159
C1	0.35	0.4	0.45	0.014	0.016	0.018
C2	1.27TYP			0.5TYP		
θ1	8°	10°	12°	8°	10°	12°
L1	0.63	0.64	0.65	0.025	0.025	0.026
L2	1.2	1.3	1.4	0.047	0.051	0.055
L3	3.415	3.42	3.425	0.134	0.135	0.135
H	0.24	0.25	0.26	0.009	0.010	0.010



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